## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HIYAMA ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0190215	12-2002	Tashiro et al.	250/370.11
	В	US-			
	С	US-			
Y	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
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	R					
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	Т					

## **NON-PATENT DOCUMENTS**

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